

### **University of Huddersfield Repository**

Hassan, Mothana A., Jiang, Xiang and Haydn, Martin

Fast surface metrology using wavelength scanning and dispersive white light interferometry

#### **Original Citation**

Hassan, Mothana A., Jiang, Xiang and Haydn, Martin (2012) Fast surface metrology using wavelength scanning and dispersive white light interferometry. In: Proceedings of The Queen's Diamond Jubilee Computing and Engineering Annual Researchers' Conference 2012: CEARC'12. University of Huddersfield, Huddersfield, p. 148. ISBN 978-1-86218-106-9

This version is available at http://eprints.hud.ac.uk/id/eprint/13484/

The University Repository is a digital collection of the research output of the University, available on Open Access. Copyright and Moral Rights for the items on this site are retained by the individual author and/or other copyright owners. Users may access full items free of charge; copies of full text items generally can be reproduced, displayed or performed and given to third parties in any format or medium for personal research or study, educational or not-for-profit purposes without prior permission or charge, provided:

- The authors, title and full bibliographic details is credited in any copy;
- A hyperlink and/or URL is included for the original metadata page; and
- The content is not changed in any way.

For more information, including our policy and submission procedure, please contact the Repository Team at: E.mailbox@hud.ac.uk.

http://eprints.hud.ac.uk/



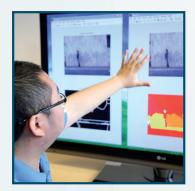
## **Diamond Jubilee**

## Proceedings of Annual Researchers' Conference 2012

# **Computing and Engineering**

# CEARC'12







Edited By Prof. Gary Lucas

Organising Committee Prof. Gary Lucas Mrs Gwen Wood Mr Chris Sentance

### Inspiring tomorrow's professionals

ISBN: 978-1-86218-106-9